

Search Notes

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Examiner

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Applicant(s)/Patent under
Reexamination

FUJII ET AL.

Art Unit

2615

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST SEARCH (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	1/19/2006	NT
348/345-357 (text search - see search history printout)	1/19/2006	NT
348/220.1 (text search - see search history printout)	1/20/2006	NT